Docket No. 741124-79

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of	)
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Michael HERMANN	) Group Art Unit: 2872
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Application No.: 09/817,797	) Examiner: Audrey Y. Chang
	:
Filed: March 27, 2001	) Confirmation No. 8356
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For: DEVICE FOR QUANTITATIVE ASSESSMENT OF THE ALIGNED POSITION OF TWO MACHINE PARTS, WORKPIECES OR THE LIKE	) :) :

CORRECTED SUMMARY OF CLAIMED SUBJECT MATTER

Mail Stop Appeal Brief-Patents
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 223 13-1450

Sir:

The following corrected *Summary of claimed subject matter* is presented in furtherance of the Notice of Appeal filed June 17, 2009, and in response to the Notification of Non-Compliant Appeal Brief issued December 7, 2009, in connection with the above-identified application.

Summary of claimed subject matter.

Claim 1

A device for measuring or evaluating the relative angular offset position of two elements with respect to each other (Fig. 3), comprising a collimated light source 20 for producing at least one light beam (25) is connected to a first of the two elements at a known location (paragraph [0018], second sentence, page 5) and a first two-dimensionally readable optoelectronic sensor (110) and at least one second two-dimensionally readable optoelectronic sensor (120) connected to a second of the two elements, each of which is in a fixed relative alignment with respect to each other (paragraph [0018], third sentence, page 5) at a known location such that a portion of the at least one light beam (25) is incident on a surface of an optoelectronically active layer of the first optoelectronic sensor (110, paragraph [0018], last sentence, page 5) and is reflected by the surface of the optoelectronically active layer as a light beam (125) directly onto a surface of the at least one second two-dimensionally readable optoelectronic sensor (120, Fig. 3). An electronic means (26) for receiving output signals from each of the optoelectronic sensors (110, 120) representing the coordinates at which the at least one light beam (25) and reflected portion of the at least one light beam (125) are detected on each respective sensor of the optoelectronic sensors (110, 120), processing the signals, and computing the relative angular offset position of the two elements with respect to each other based on the coordinates detected (paragraph [0019], spanning pages 5 & 6).

Claim 3

A device for measuring or evaluating the relative angular offset position of two elements with respect to each other (Fig. 3), comprising a collimated light source 20 for producing at least one light beam (25) is connected to a first of the two elements at a known location (paragraph [0018], second sentence, page 5) and a first two-dimensionally readable optoelectronic sensor (110) and at least one second two-dimensionally readable optoelectronic sensor (120). A housing (100, 500) is connected to a second of the two elements at a known location, in which the first and second two-dimensionally readable optoelectronic sensors (110, 120) are positioned

relative to one another at a known location with respect to said housing such that a portion of the light beam (25) incident on the first two-dimensionally readable optoelectronic sensor (110) is reflected as a plurality of light beams (225, 325) in a folded beam path by a surface of an optoelectronically active layer of the first optoelectronic sensor (110) directly onto the second two-dimensionally readable optoelectronic sensor (120). A portion of the light beam incident on the first two-dimensionally readable optoelectronic sensor is reflected as a plurality of light beams (125, 225, 325; Fig. 4) in a folded beam path (125, 125'; Fig. 5 modification of Fig. 4) by a surface of an optoelectronically active layer of the first optoelectronic sensor (110) directly onto the second two-dimensionally readable optoelectronic sensor (see paragraphs [0021] and [0022], page 6). An electronic means (26) is provided for receiving output signals from each of the optoelectronic sensors (110, 120) representing the coordinates at which the at least one light beam (25) and reflected portion of the at least one light beam (125) are detected on each respective sensor of the optoelectronic sensors (110, 120), processing the signals, and computing the relative angular offset position of the light source means (20) relative to the coordinates of incidences of the at least one light beam on the surfaces of the two dimensionally readable optoelectronic sensors (110, 120).

Claim 4

A device for measuring or evaluating the relative angular offset position of two elements with respect to each other (Fig. 3), comprising a collimated light source 20 for producing at least one light beam (25) is connected to a first of the two elements at a known location (paragraph [0018], second sentence, page 5), a first two-dimensionally readable optoelectronic sensor (110) and at least one second two-dimensionally readable optoelectronic sensor (120) connected to a second of the two elements, each of which is in a fixed relative alignment with respect to each other (paragraph [0018], third sentence, page 5) at a known location such that a portion of the at least one light beam (25) is incident on a surface of an optoelectronically active layer of the first optoelectronic sensor (110, paragraph [0018], last sentence, page 5) and is reflected by the surface of the optoelectronically active layer as a light beam (125) directly onto a surface of the

at least one second two-dimensionally readable optoelectronic sensor (120, Fig. 3). An electronic means (26) is provided for receiving output signals from each of the optoelectronic sensors (110, 120) representing the coordinates at which the at least one light beam (25) and reflected portion of the at least one light beam (125) are detected on each respective sensor of the optoelectronic sensors (110, 120), processing the signals, and computing the relative angular offset position of the light source means (20) relative to the coordinates of incidences of the at least one light beam on the surfaces of the two-dimensionally readable optoelectronic sensors (110, 120).

On the basis of the above, the Appeal Brief should not be in full compliance, so that issuance of an Examiner's Answer is now in order.

Respectfully submitted,

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